UNITED STATES DEPARTMENT OF COMMERCE United States Patent and Trademark Office Address: COMMISSIONER FOR PATENTS P.O. Box 1450 Alexandria, Virginia 22313-1450 www.uspto.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/593,557	11/17/2006	Yasuhiko Kasama	8075-1111	4919
466 YOUNG & TH	7590 10/14/200 OMPSON	EXAMINER		
209 Madison St		ANGADI, MAKI A		
	Suite 500 ALEXANDRIA, VA 22314			PAPER NUMBER
			1792	
			MAIL DATE	DELIVERY MODE
			10/14/2009	PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

	Application No.	Applicant(s)		
	10/593,557	KASAMA ET AL.		
Office Action Summary	Examiner	Art Unit		
	MAKI A. ANGADI	1792		
The MAILING DATE of this communication app Period for Reply	pears on the cover sheet with the c	orrespondence address		
A SHORTENED STATUTORY PERIOD FOR REPLY WHICHEVER IS LONGER, FROM THE MAILING DA  - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication.  - If NO period for reply is specified above, the maximum statutory period v  - Failure to reply within the set or extended period for reply will, by statute, Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATION 36(a). In no event, however, may a reply be tim vill apply and will expire SIX (6) MONTHS from a cause the application to become ABANDONE	lely filed the mailing date of this communication. (35 U.S.C. § 133).		
Status				
1) ☐ Responsive to communication(s) filed on <u>07 At</u> 2a) ☐ This action is <b>FINAL</b> . 2b) ☐ This 3) ☐ Since this application is in condition for allowar closed in accordance with the practice under E	action is non-final. nce except for formal matters, pro			
Disposition of Claims				
4) ☐ Claim(s) 3-7 and 9-17 is/are pending in the appear 4a) Of the above claim(s) is/are withdraw 5) ☐ Claim(s) is/are allowed. 6) ☐ Claim(s) 3-7 and 9-17 is/are rejected. 7) ☐ Claim(s) is/are objected to. 8) ☐ Claim(s) are subject to restriction and/or Application Papers 9) ☐ The specification is objected to by the Examine	wn from consideration. r election requirement.			
10) The drawing(s) filed on is/are: a) acceed to by the Examine 10). The drawing(s) filed on is/are: a) acceed Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct 11). The oath or declaration is objected to by the Examine 10.	epted or b) objected to by the Eddrawing(s) be held in abeyance. See ion is required if the drawing(s) is obj	e 37 CFR 1.85(a). ected to. See 37 CFR 1.121(d).		
Priority under 35 U.S.C. § 119				
<ul> <li>12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).</li> <li>a) All b) Some * c) None of:</li> <li>1. Certified copies of the priority documents have been received.</li> <li>2. Certified copies of the priority documents have been received in Application No</li> <li>3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).</li> <li>* See the attached detailed Office action for a list of the certified copies not received.</li> </ul>				
Attachment(s)  1) Notice of References Cited (PTO-892)  2) Notice of Draftsperson's Patent Drawing Review (PTO-948)  3) Information Disclosure Statement(s) (PTO/SB/08) Paper No(s)/Mail Date 9/25/2009.	4)  Interview Summary Paper No(s)/Mail Da 5)  Notice of Informal P 6)  Other:	ite		

Art Unit: 1792

#### **DETAILED ACTION**

#### Continued Examination Under 37 CFR 1.114

1. A request for continued examination under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action has been withdrawn pursuant to 37 CFR 1.114. Applicant's submission filed on 8/7/2009 has been entered.

2. Examiner has entered amendments to the specification and claims filed on 8/7/2009.

## Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

This application currently names joint inventors. In considering patentability of the claims under 35 U.S.C. 103(a), the examiner presumes that the subject matter of the various claims was commonly owned at the time any inventions covered therein were made absent any evidence to the contrary. Applicant is advised of the obligation under 37 CFR 1.56 to point out the inventor and invention dates of each claim that was not commonly owned at the time a later

Art Unit: 1792

invention was made in order for the examiner to consider the applicability of 35 U.S.C. 103(c) and potential 35 U.S.C. 102(e), (f) or (g) prior art under 35 U.S.C. 103(a).

3. Claims 3-6, 9, 12 and 17 are rejected under 35 U.S.C. 103(a) over Miley et al. (US Patent No. 6,171,451) in view of Chang Robert (US Patent No. 5,916,642).

As to claims 3 and 6, Miley discloses a fullerene production method (col.5, lines 6-11) that comprises: generating plasma (Fig.1, col.6, lines 59-60) containing target ions in spherical volume vessel (Fig.1A, col.6, lines 61-62); applying a control voltage (col.6, line 60) to an electric potential body/grid (col.6, line 61-64) in contact with plasma to control density of the target ions (col.7, lines 1-4); irradiating plasma towards deposition assistance substrate and fullerene is deposited at the bottom of the chamber (col.10, lines 15-18) (Fig.2); applying a bias voltage (col.13, lines 52-67, claim 18) of a polarity opposite to that of the target ions with acceleration energies (col.9, lines 65-67, col. 10, lines 1-10); applying bias voltage to provide containment ions and generate material molecules to internally contain target ions (col.14, lines 25-31). It is noted that the lower chamber region serves the role of substrate to collect fullerene.

Miley discloses the presence of ions in the fullerene production unit (col.7, lines 54-60, col.9, lines 65-67) but does not explicitly disclose collision ions. However, Miley's production apparatus discloses an electrical discharge in the hydrocarbon gas resulting in molecules and ionization of component atoms under

grid voltage (col.9, line 57). Therefore, one would expect the generation of collision ions in the production apparatus in addition to target ions are generated in the presence of external voltage.

Miley does not explicitly disclose a method to produce encapsulating-fullerenes or encapsulating-nanotubes. However, Chang discloses a method of encapsulating a material e.g. copper, germanium in a carbon nanotube (col.1, lines 61-67 and col.2, lines 1-5, Fig. 3B and 3C). Therefore, it would have been obvious to one of ordinary skill in the art at the time of the invention was made to select encapsulating-nanotubes in the process employed by Miley because Chang illustrates in Fig.2B and Fig.2C that the encapsulating-nanotubes with metal or a semiconductor material can be used as electron emitters in flat panel disclpays for visual display devices and nanowires (after nanotube is removed) for electrical interconnects for connecting IC chips (col.6, lines 28-33).

As to claims 4-5, Miley discloses a production apparatus for producing fullerene molecules (Fig.2) (col.5, lines 6-11) by generating plasma (col.6, lines 590-60) on deposition assistance substrate (lower chamber region) by plasma irradiation (col.6, lines 58-65).

As to claim 9, Miley discloses implantation target ions are cesium, argon, hydrogen, helium, nitrogen ions (col.14, lines 48-53).

As to claim 12, Miley discloses that the production method comprises fullerene (col.5, lines 31-35) and collision ions are fullerene positive or negative

Art Unit: 1792

ions depending on target substance, propellant gas and applied voltage (Fig.11, col.47-65).

As to claim 17, Miley discloses ion density profiles in Fig.1C and 1D by measuring an electric current flowing between the substrate to measure the density of target ions (col.7, lines 43-61 and col.11, lines 36-57).

# Claim Rejections - 35 USC § 103

4. Claims 7, 13-16 are rejected under 35 U.S.C. 103(a) over Miley et al. (US Patent No. 6,171,451) in view of Chang Robert (US Patent No. 5,916,642) as applied to claim 6, and in further view of Fetherston et al. (US Patent No. 5,693,376).

Miley discloses a production apparatus for producing fullerene (Fig.2) comprising a vacuum vessel (111); plasma generation means for generating plasma (col.9, lines 55-57) including generating target ions (col.9, lines 65-67); collision ions (col.11, lines 36-48); a substrate (in the lower chamber region, 125); bias power supply for applying bias voltage from 100V to about -1kV (col.14, lines 64-65) to measure density of target ions (col.13, lines 64-67 and col.14, lines 13-16); electric potential body (or wall structure) in a lattice pattern (Fig.9, lines 24-29); target molecules depositing on the substrate (Fig.6A, col.12, lines 4-23); fullerene ions that would include positive and negative ions because of the electrical potential difference between the wall of the chamber 11 and the grid 112 (col.9, lines 65-67 and col.10 lines 1-10).

Art Unit: 1792

Miley is silent about the use of magnetic field generation means. However,

Fetherston discloses the use of magnetic bars (13) distributed about the outer

periphery of the chamber wall (12) to generated magnetic field to influence ions

generated by the plasma (col.5, lines 16-29, Fig.2).

Therefore, it would have been obvious to one of ordinary skill in the art at the

time of the invention was made to employ magnetic field lines around the plasma

chamber employed by Miely because Fetherston illustrates that the presence of

magnetic field will enhance ionization of gas molecules in the production of

materiel film (col.5 lines 28-39).

Miley does not explicitly disclose a method to produce encapsulating-

fullerenes or encapsulating-nanotubes. However, Chang discloses a method of

encapsulating a material e.g. copper, germanium in a carbon nanotube (col.1,

lines 61-67 and col.2, lines 1-5, Fig. 3B and 3C). Therefore, it would have been

obvious to one of ordinary skill in the art at the time of the invention was made to

select encapsulating-nanotubes in the process employed by Miley because

Chang illustrates in Fig.2B and Fig.2C that the encapsulating-nanotubes with

metal or a semiconductor material can be used as electron emitters in flat panel

displays for visual display devices and nanowires (after nanotube is removed)

for electrical interconnects for connecting IC chips (col.6, lines 28-33).

Claim Rejections - 35 USC § 103

5. Claims 10 is rejected under 35 U.S.C. 103(a) over Miley et al. (US Patent No. 6,171,451) in view of Chang Robert (US Patent No. 5,916,642) as applied to claims 3 and 6, in further view of Takehara et al. (US pub. No. 2005/0129607).

Page 7

Miley is silent about the use of target substance such as TTF, anthracene, pentacene etc. in the production of material film. However, Takehara discloses the use of anthracene, naphthalene and phenanthracene in the production of fullerene (paragraph 0022, 0045). Therefore, it would have been obvious to one of ordinary skill in the art at the time of the invention was made to select anthracene and other target material in the production of material film because Takehara discloses that the hydrocarbon fuel such as anthracene reacts with oxygen to generate heat, thereby raising a gas temperature to a degree sufficient to produce material film such as fullerene (paragraph 0046).

## Claim Rejections - 35 USC § 103

6. Claim 11 is rejected under 35 U.S.C. 103(a) over Miley et al. (US Patent No. 6,171,451) in view of Chang Robert (US Patent No. 5,916,642) as applied to claim 3, in further view of Liu et al. Chemical Physics Letters, 331 (2000), pages 31-34.

Miley is silent about the size of the collision ions in the production of fullerene. However, Liu discloses the size of the collision carbon nanorods or fullerenes in the range 15-50 nm (page 32, paragraph 1) with a mean free path of 15  $\mu$ m for carbon-carbon collision (page 33, paragraph 4). Therefore, it would have been obvious to one of ordinary skill in the art at the time of the invention

was made to select the size of the collision ions and hence the size of nanotubes because Liu illustrates in Fig. 1 that the structural characteristics of the ionic collision of carbon ions during discharge process are responsible for building a longer nanotubes.

## Response to Arguments

7. Applicant's arguments on pages 10-13 with respect to claims 3-7 and 9-17 have been considered but are moot in view of the new ground(s) of rejection. The new reference of Chang (US Patent No. 5,916,642) discloses a method of encapsulating a material in a carbon nanotube. Therefore, the combined reference of Mlley and Chang meet the limitations of amended independent claims.

#### Conclusion

The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. Anazawa et al. (US Patent No. 6,902,655) discloses a producing apparatus and production method for manufacturing carbon structure.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to MAKI A. ANGADI whose telephone number is (571)272-8213. The examiner can normally be reached on 8 AM to 4.30 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Nadine G. Norton can be reached on 571-272-1465. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Art Unit: 1792

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-

/Maki A Angadi/ Examiner, Art Unit 1792

/Shamim Ahmed/ Primary Examiner, Art Unit 1792

9199 (IN USA OR CANADA) or 571-272-1000.